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(12) **United States Design Patent** (10) **Patent No.:** **US D803,195 S**
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(54) **RFID TAG INLAY**
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See application file for complete search history.

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(57) **CLAIM**

The ornamental design for an RFID tag inlay, as shown and described.

DESCRIPTION

The sole FIGURE is a front elevational view of an RFID tag inlay showing my new design. All elements of the claimed design are flat and coplanar.

1 Claim, 1 Drawing Sheet



